

IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Neal W. Meyer et al.

Confirmation No.:

Application No.: Unknown

Examiner: Unknown

Filing Date: Herewith

Group Art Unit: Unk.

Title: STORAGE STRUCTURE WITH CLEAVED LAYER

Commissioner for Patents

PO Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

- (X) under 37 CFR 1.97(b), or
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
- () under 37 CFR 1.97(c) together with either a:
() Statement under 37 CFR 1.97(e), or
() a \$180.00 fee under 37 CFR 1.17(p), or
(After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
- () under 37 CFR 1.97 (d) together with a:
() Statement under 37 CFR 1.97(e)(1) or (2), and
() a \$180.00 fee set forth in 37 CFR 1.17(p).
(Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account **08-2025** the sum of \$0.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account **08-2025** pursuant to 37 CFR 1.25.

(X) Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Statement together with any required copies of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

() A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individual(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

"Express Mail" label no. **EV409552625US**

Respectfully submitted,

Date of Deposit Nov. 20, 2003

Neal W. Meyer et al.

I hereby certify that this is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to: Commissioner for Patents, Alexandria, VA 22313-1450.

By Michelle A. Dunn

William M. Hinz III

By Michelle A. Dunn
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Attorney/Agent for Applicant(s)
Reg. No. **37,069**

Date: **Nov. 20, 2003**

FORM PTO-1449		ATTY. DOCKET NO.	APPLICATION NO.	CONFIRMATION NO.
		10017494-1		
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		APPLICANT		
(Use several sheets if necessary)		Neal W. Meyer et al.		
		FILING DATE	GROUP	
		Herewith		

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	1A	5,636,441	06-1997	Meyer et al.	
	1B	5,682,188	10-1997	Meyer et al.	
	1C	5,851,902	12-1998	Sakai	
	1D	6,248,649	06-2001	Henley et al.	
	1E	6,315,393	11-2001	Van Nice et al.	
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L					
	1M					
	1N					
	1O					
	1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

	1Q	Simonton, Robert, "SOI Wafer Technology for CMOS ICs", 2002, Simonton Associates, pp. 1-11.
	1R	"Soitec Buys Selected Assets of Picogiga", April 1, 2003, www.compoundsemiconductor.net/articles/news/7/4/1/1 , pp. 1-2.
	1S	SiGen Research and Development Programs, www.sigen.com/research.htm , pp. 1-3.

EXAMINER

DATE CONSIDERED